

Abstract

**SOCKET OR ADAPTER DEVICE FOR SEMICONDUCTOR DEVICES, METHOD
FOR TESTING SEMICONDUCTOR DEVICES, AND SYSTEM COMPRISING AT
5 LEAST ONE SOCKET OR ADAPTER DEVICE**

The invention relates to a method for testing semiconductor devices, to a system including at least one socket or adapter device, and to a socket or adapter device, in particular for semiconductor devices, including at least one
10 connection pin which is designed to be adapted to be connected to a corresponding contact device of a device, wherein the connection pin is designed such that it can be connected to the contact device by surface mounting, in particular
15 by solderless surface mounting.